### Certificate TW18/10154

The management system of

# **Ardentec Corporation**



KS, No. 24, Wenhua Rd., Hsin-Chu Industrial Park, Hukou Township, Hsinchu County 303035, Taiwan, R.O.C.

has been assessed and certified as meeting the requirements of

IEC 61340-5-1:2016

For the following activities

The manufacture of WLCSP and trimmed integrated circuits.

The production testing of semiconductor device.

ESD Program Manager: Irene Ou

Further clarifications regarding the scope of this certificate and the applicability of IEC 61340-5-1:2016

requirements may be obtained by consulting the organization.

Lead Auditor: Michael Chiu

Certification Manager: Roger S. Villanueva

This certificate is valid from 19 July 2025 until 18 July 2026

Issue 8. Certified since 19 July 2018

Certified activities performed by additional sites are listed on subsequent pages.

Authorised by

Roger Villanueva

SGS Philippines, Inc.

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## Certificate TW18/10154, continued

## **Ardentec Corporation**



IEC 61340-5-1:2016

Issue 8

#### Sites

Ardentec Corporation

KS, No. 24, Wenhua Rd., Hsin-Chu Industrial Park, Hukou Township, Hsinchu County 303035, Taiwan, R.O.C.

The manufacture of WLCSP and trimmed integrated circuits.

**Ardentec Corporation** 

TSP1, TSP2, TSOB, No. 3, Gongye 3rd Rd., Hsin-Chu Industrial Park, Hukou Township, Hsinchu County 303036, Taiwan, R.O.C.

The production testing of semiconductor device.

Ardentec Corporation

GS, No. 9, Renyi Rd., Hsin-Chu Industrial Park, Hukou Township, Hsinchu County 303035, Taiwan, R.O.C.

The production testing of semiconductor device.

Ardentec Corporation

PS, 1st, 6th Floor and 7th Floor, No. 12, Guangfu N. Rd., Hsin-Chu Industrial Park, Hukou Township, Hsinchu County 303036, Taiwan, R.O.C.

The production testing of semiconductor device.

Ardentec Corporation

ADTN, No.29, Qiuyun Road, Qiaolin Street, Pukou District, Nanjing City, Jiangsu Province, P.R. China

The production testing of semiconductor device.



